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PCI-4474

NI 447x Specifications

Français	Deutsch	日本語	한국어	简体中文
ni.com/manuals				

This document lists specifications for the NI 447x Dynamic Signal Acquisition (DSA) devices including the NI PXI/PCI-4472 (NI 4472), NI PCI-4474, and NI PXI/PCI-4472B (NI 4472B). These specifications are typical at 25 °C unless otherwise stated. The system must be allowed to warm up for 15 minutes to achieve the rated accuracy. All specifications are subject to change without notice. Visit ni.com/manuals for the most current specifications and product documentation.



Caution The inputs of this sensitive test and measurement product are not protected for electromagnetic interference for functional reasons. As a result, this product may experience reduced measurement accuracy or other temporary performance degradation when cables are attached in an environment with electromagnetic interference present. Refer to the Declaration of Conformity (DoC) for this product for details of the standards applied to assess electromagnetic compatibility performance. To obtain the DoC, visit ni.com/certification, search by model number or product line, and click the appropriate link in the Certification column.

Sample rates (f_s) ,



Note Keep the filler panels on all unused slots in your chassis or computer to maintain forced air cooling.

Analog Input

Number of channels

Channel Characteristics

		~ V S/,	
NI 4472/4472B	•	samples-per-second (S/s)	102.4 kS/s down to 1.0 kS/s in 190.7 µS/s
NI PCI-4474	sampled 4, simultaneously sampled		increments for $f_s > 51.2$ kS/s or 95.37 μ S/s increments for
Input configuration	Pseudodifferential		$f_{\rm s} \le 51.2 \text{ kS/s}$
Input coupling	AC or DC, software-selectable	ADC modulator oversample rate $1.0 \text{ kS/s} \le f_s \le 51.2 \text{ kS/s} \dots$	128 f _s
A/D converter (ADC) resolution	24 bits	$51.2 \text{ kS/s} < f_{\text{s}} \le 102.4 \text{ kS/s} \dots$	64 $f_{\rm s}$
ADC type	Delta-sigma	Sample Clock Timebase, low-free disabled (default) ¹	quency alias rejection
		$1.0 \text{ kS/s} \le f_{s} \le 51.2 \text{ kS/s} \dots$	256 $f_{\rm s}$
		$51.2 \text{ kS/s} < f_{\text{s}} \le 102.4 \text{ kS/s} \dots$	$128 f_{\rm s}$



Low-frequency alias rejection can be enabled at sample rates of 25.6 kS/s and lower for supported NI 447x devices. Refer to the National Instruments Dynamic Signal Acquisition Help for supported devices and more information.

Sample Clock Timebase, low-frequency alias rejection enabled

Sample Rate (kS/s)	Sample Clock Timebase
$1.0 \le f_{\rm s} \le 1.6$	8,192 f _s
$1.6 < f_{\rm s} \le 3.2$	$4,096 f_{\rm s}$
$3.2 < f_s \le 6.4$	$2,048 f_{\rm s}$
$6.4 < f_{\rm s} \le 12.8$	$1,024 f_{\rm s}$
$12.8 < f_{\rm s} \le 25.6$	512 f _s
$25.6 < f_{\rm s} \le 51.2$	256 f _s
$51.2 < f_s \le 102.4$	$128 f_{\rm s}$

Frequency accuracy ±25	ppm
Input signal range±10	V_{nk}

Transfer Characteristics

DC-coupled offset (residual) ±3 mV, max

Gain (amplitude accuracy)..... ± 0.1 dB, max, $f_{in} = 1$ kHz

Amplifier Characteristics

Input Impedance (Ground Referenced)	Pseudodifferential Configuration
Between positive input and chassis ground (NI 447x all revisions and NI PXI-4472B revision G and earlier)	1 MΩ 60 pF
Between positive input and chassis ground (NI PXI-4472B revision H and later)	10 MΩ 60 pF
Between negative input and chassis ground	50 Ω 0.02 μF

Common-mode rejection ratio (CMRR) Input frequency $(f_{in}) < 1 \text{ kHz.....} 60 \text{ dB}$

Dynamic Characteristics

Specification	Low-Frequency Alias Rejection Disabled (Default)	Low-Frequency Alias Rejection Enabled
Alias-free bandwidth (BW) (passband)	DC to 0.4535 f _s	DC to 0.4 f _s
Alias rejection, minimum	110 dBc	104 dBc
Alias rejection by frequency	0.5465 f_s < input frequency < 127.4535 f_s , where 1.0 kS/s $\leq f_s \leq$ 51.2 kS/s 0.5465 f_s < input frequency < 63.4535 f_s , where 51.2 kS/s < $f_s \leq$ 102.4 kS/s	Input frequency $> 0.6 f_s$
-3 dB BW	0.491 f _s	$0.4863 f_{\rm s}$

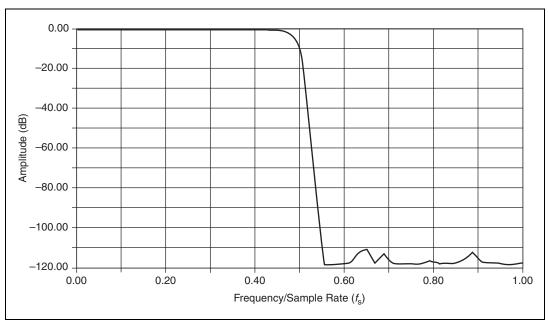


Figure 1. Digital Filter Input Frequency Response

Aliasing can occur for frequencies around multiples of 128 or $64 f_s$ with low-frequency alias rejection disabled. In Figure 2, the solid line shows the amount of rejection for signals that appear in the f_s -wide windows around multiples of 128 or $64 f_s$.

The dashed line shows the improvement achieved with low-frequency alias rejection enabled. Refer to the *National Instruments Dynamic Signal Acquisition Help* for more information.

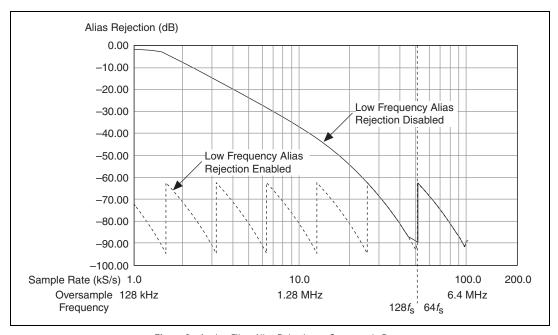


Figure 2. Analog Filter Alias Rejection at Oversample Rates

Low-Frequency Alias Rejection Disabled (Default)		Low-Frequency Alias Rejection Enabled	
Sample Rate (kS/s)	Filter Delay (Samples)	Sample Rate (kS/s)	Filter Delay (Samples)
$1.0 \le f_{\rm s} \le 1.6$	38.7	$1.0 \le f_{\rm s} \le 1.6$	32
$1.6 < f_s \le 3.2$		$1.6 < f_s \le 3.2$	32
$3.2 < f_s \le 6.4$		$3.2 < f_s \le 6.4$	32
$6.4 < f_{\rm s} \le 12.8$		$6.4 < f_{\rm s} \le 12.8$	33.675
$12.8 < f_s \le 25.6$		$12.8 < f_s \le 25.6$	35.35
$25.6 < f_{\rm s} \le 102.4$		$25.6 < f_s \le 102.4$	38.7

AC –3 dB cut-off frequency	
NI 447x	3.4 Hz
NI 4472B	0.5 Hz

Flatness, relative to 1 kHz, DC coupled, for sample rate $1.0 \text{ kS/s} \le f_s \le 51.2 \text{ kS/s} \dots \pm 0.03 \text{ dB}$, max $51.2 \text{ kS/s} < f_s \le 102.4 \text{ kS/s} \dots \pm 0.1 \text{ dB}$, max

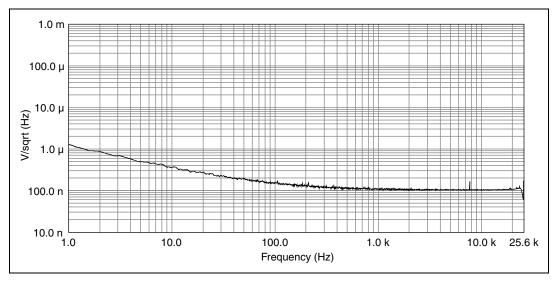


Figure 3. Input Noise Spectral Density at 128-Times Oversampling (50 Ω Connected at Input)

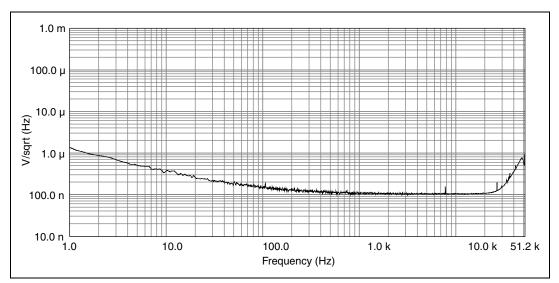


Figure 4. Input Noise Spectral Density at 64-Times Oversampling (50 Ω Connected at Input)

Idle channel noise, for sample rate

```
f_{\rm s} = 51.2 \text{ kS/s},
bandwidth = 25.6 kHz .....-94 dBV<sub>rms</sub>
f_{\rm s} = 102.4 \text{ kS/s},
bandwidth = 51.2 kHz .....-81 dBV<sub>rms</sub>
```

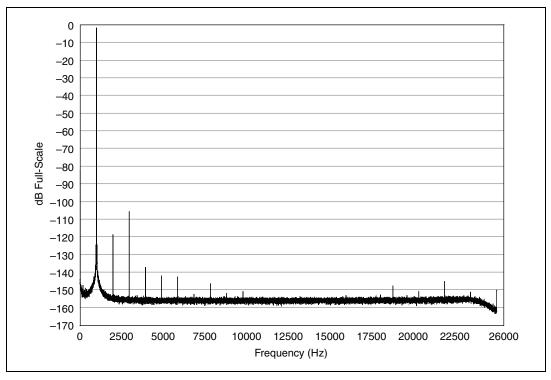


Figure 5. SFDR 51.2 kS/s (-1 dBFS, 1 kHz Sine Wave Input, FFT Size 131,072 Samples, Five Averages)

¹ Measurement includes all harmonics.

 $^{^2\,}$ 1 kHz input tone, input amplitude is –1 dBFS or 8.91 $V_{pk}.$

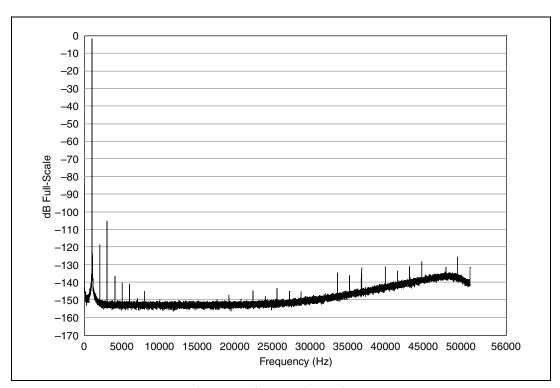


Figure 6. SFDR 102.4 kS/s (-1 dBFS, 1 kHz Sine Wave Input, FFT Size 131,072 Samples, Five Averages)

¹ Bandwidth equals $0.4535 f_8$ starting from 20 Hz.

² 1 kHz input tone, input amplitude is -60 dBFS.

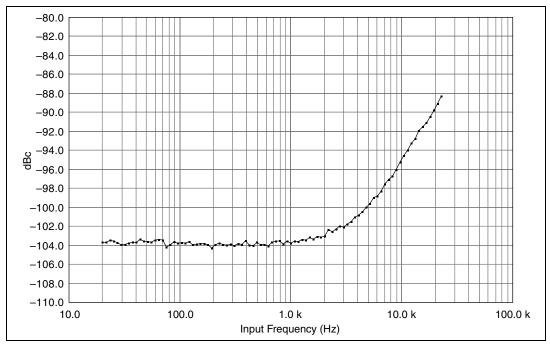


Figure 7. THD (Unbalanced Source, 102.4 kS/s), -1 dBFS Input Sine Wave, DC Coupled

THD+N ²	–97 dBc
IMD	100 dBc
	(CCIF 14 kHz + 15 kHz)

ıd
dB
dB

^{*} Measured with full-scale (±10 V) input.

 $^{\dagger} f_{\rm in} = 0 \text{ to } 51.2 \text{ kHz}$

$$\begin{split} &\text{Interchannel gain mismatch, for sample rate} \\ &1.0 \text{ kS/s} \leq f_\text{s} \leq 51.2 \text{ kS/s} \dots \pm 0.06 \text{ dB, max} \\ &51.2 \text{ kS/s} < f_\text{s} \leq 102.4 \text{ kS/s} \dots \pm 0.2 \text{ dB, max} \\ &\text{Interchannel phase mismatch} \dots \leq f_\text{in} (\text{in kHz}) \times 0.018^\circ + 0.082^\circ \end{split}$$

Phase linearity<±0.5°

Onboard Calibration Reference

DC level	5.000 V ±2.5 mV
Temperature coefficient	±5 ppm/°C max
Long-term stability	±20 ppm/ √1,000 h

Integrated Electronic Piezoelectric (IEPE)

	channel independently software selectable
Compliance	24 V
Output impedance	>250 kΩ at 1 kHz
Current noise	<500 pA/√Hz

¹ 1 kHz input tone, input amplitude is –1 dBFS.

² 1 kHz input tone, -1 dBFS, 50 kHz measurement bandwidth.

Triggers		Physical	
Analog trigger		Dimensions (not including conne	ctors)
Purpose	Start trigger or reference	NI PCI-4472/4472B/4474	$17.5 \times 10.7 \text{ cm}$
Source			$(6.9 \times 4.2 \text{ in.})$
NI 4472/4472B	CH<07>	NI PXI-4472/4472B	
NI PCI-4474	CH<03>		(6.3 × 3.9 in.) (1 3U CompactPCI slot)
Level	Full scale, programmable		(1 30 Compacti Ci siot)
Slope	Positive (rising) or	Weight	
	negative (falling),	NI PCI-4472/4472B	e , ,
	software-selectable	NI PCI-4474	e . ,
Resolution		NI PXI-4472/4472B	241 g (8.5 oz)
Hysteresis	Programmable	Analog I/O connectors	SMB male
Digital trigger		Digital trigger connector	SMB male
Purpose			
Compatibility		Environmental	
Polarity		Operating Environment	
Minimum pulse width	100 ns	Ambient temperature range	
Canaval Chaoifiaction	_	PXI-447x	0 to 55 °C
General Specification	S		(Tested in accordance
Bus Interface			with IEC-60068-2-1 and
PCI or PXI	3.3 V or 5 V signal	DGL 445	IEC-60068-2-2.)
	environment	PCI-447x	0 to 50 °C (Tested in accordance
DMA channels	1, analog input		with IEC-60068-2-1 and
			IEC-60068-2-2.)
Synchronization		Relative humidity range	10 to 90%
PXI		Relative numerty range	noncondensing
PXI_STAR			(Tested in accordance
	chassis		with IEC-60068-2-56.)
PCI		Altitude	2,000 m (at 25 °C ambient
RTSI	1		temperature)
	ribbon cable	Pollution Degree	
Power Requirements		(indoor use only)	2
+3.3 VDC			
NI PCI-4472/4472B/4474	0 mA	Storage Environment	20 . 50 00
NI PXI-4472/4472B		Ambient temperature range	–20 to 70 °C (Tested in accordance
			with IEC-60068-2-1 and
+5 VDC	2 (00 4		IEC-60068-2-2.)
NI PCI-4472/4472B		Relative humidity range	5 to 95% noncondensing
NI PCI-4474 NI PXI-4472/4472B		relative numberly runge	(Tested in accordance
			with IEC-60068-2-56.)
+12 VDC	120 mA, max		
-12 VDC	120 mA, max		

Shock	and	Vibration	(PXI	Only	١

Operational shock	30 g peak, half-sine,
	11 ms pulse
	(Tested in accordance
	with IEC-60068-2-27.
	Test profile developed in
	accordance with
	MIL-PRF-28800F.)
Random vibration	

Operating	5 to 500 Hz, 0.3 g _{rms}
Nonoperating	5 to 500 Hz, 2.4 g _{rms}
	(Tested in accordance
	with IEC-60068-2-64.
	Nonoperating test profile
	exceeds the requirements
	of MIL-PRF-28800F,
	Class 3.)

Calibration

Self-calibration	On software command
SCI-Canoradon	the device computes gain and offset corrections relative to high-precision internal reference
Interval	.Recommended whenever ambient temperature differs from T_{cal} by more than $\pm 5~^{\circ}C$
External calibration interval	1 year
Warm-up time	15 minutes

Maximum Working Voltage

Maximum working voltage refers to the signal voltage plus the common-mode voltage.

Channel-to-earth	42 V _{pk} , Measurement
	Category I
Channel-to-channel	42 V _{pk} , Measurement
	Category I



Caution Do not use the NI 447x for connections to signals or for measurements within Categories II, III. or IV.

Safety

This product meets the requirements of the following standards of safety for electrical equipment for measurement, control, and laboratory use:

- IEC 61010-1, EN 61010-1
- UL 61010-1, CSA 61010-1



Note For UL and other safety certifications, refer to the product label or the Online Product Certification section.

Electromagnetic Compatibility

This product meets the requirements of the following EMC standards for electrical equipment for measurement, control, and laboratory use:

- EN 61326 (IEC 61326): Class A emissions; Basic immunity
- EN 55011 (CISPR 11): Group 1, Class A emissions
- AS/NZS CISPR 11: Group 1, Class A emissions
- FCC 47 CFR Part 15B: Class A emissions
- ICES-001: Class A emissions



Note For the standards applied to assess the EMC of this product, refer to the Online Product Certification section.



Note For EMC compliance, operate this device with shielded cables.



Note For EMC compliance, operate this product according to the documentation.

CE Compliance

This product meets the essential requirements of applicable European Directives as follows:

- 2006/95/EC; Low-Voltage Directive (safety)
- 2004/108/EC; Electromagnetic Compatibility Directive (EMC)

Online Product Certification

Refer to the product Declaration of Conformity (DoC) for additional regulatory compliance information. To obtain product certifications and the DoC for this product, visit ni.com/certification, search by model number or product line, and click the appropriate link in the Certification column.

Environmental Management

NI is committed to designing and manufacturing products in an environmentally responsible manner. NI recognizes that eliminating certain hazardous substances from our products is beneficial to the environment and to NI customers.

For additional environmental information, refer to the *NI* and the Environment Web page at ni.com/environment. This page contains the environmental regulations and directives with which NI complies, as well as other environmental information not included in this document.

Waste Electrical and Electronic Equipment (WEEE)



EU Customers At the end of the life cycle, all products *must* be sent to a WEEE recycling center. For more information about WEEE recycling centers and National Instruments WEEE initiatives, visit ni.com/environment/weee.

电子信息产品污染控制管理办法 (中国 RoHS)



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